

## Tuning circuits in systems of built-in testing

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### Abstract

Systems of built-in testing contain a test generator and a signature analyzer (SA). At last time expedience of the generator and SA selection for testing a given plant has been cleared up. Realization of this requirement assumes the modification possibility of a generator and a SA. Besides, in the case of multi-input SA efficiency of SA application over the fields  $(GF(2^m))$  ( $m > 1$ ) has been proved. In this case circuits realizing the elements product in these fields are required. A regular tuning structure is suggested for calculation of the product of matrix into vector over the field  $GF(2)$ . Possible its applications in tuning test generators and SA in systems of built-in testing are shown.

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